


**PRODUCT / PROCESS CHANGE NOTIFICATION**

**1. PCN basic data**

1.1 Company		STMicroelectronics International N.V
1.2 PCN No.	AMS/19/11662	
1.3 Title of PCN	Power Management BU: Additional tester for Test & Finishing in Muar for ALED1262xx product Family.	
1.4 Product Category	ALED1262xx product Family	
1.5 Issue date	2019-07-04	

**2. PCN Team**

2.1 Contact supplier	
2.1.1 Name	ROBERTSON HEATHER
2.1.2 Phone	+1 8475853058
2.1.3 Email	heather.robertson@st.com
2.2 Change responsibility	
2.2.1 Product Manager	Lorenzo NASO
2.1.2 Marketing Manager	Marcello SAN BIAGIO
2.1.3 Quality Manager	Sergio Tommaso SPAMPINATO

**3. Change**

3.1 Category	3.2 Type of change	3.3 Manufacturing Location
Equipment (EWS-FT)	New tester, or prober option or major HW changes (ex: computer), brand or model (Unknown type)	ST Muar

**4. Description of change**

	Old	New
4.1 Description	Current Testing Platform: SZ //2	New Testing Platform: SZ //2 and ETS363 // 4
4.2 Anticipated Impact on form,fit, function, quality, reliability or processability?	No changes of the Electrical Characteristics and Quality.	

**5. Reason / motivation for change**

5.1 Motivation	Following Divisional commitments towards a continuous improvement philosophy a New Testing Platform will be utilised for ALED1262xx product family. The new Testing platform will bring to have a major testing capacity of the IC and consequently a higher production flexibility that it is translated in a better Service versus our Customers.
5.2 Customer Benefit	SERVICE IMPROVEMENT

**6. Marking of parts / traceability of change**

6.1 Description	The traceability of the new parts will be ensured by different internal codification and QA number.
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**7. Timing / schedule**

7.1 Date of qualification results	2019-06-06
7.2 Intended start of delivery	2019-10-10
7.3 Qualification sample available?	Upon Request

**8. Qualification / Validation**

8.1 Description	11662 U1K2 Muar FT Additional Testing Platform_official_summary.pdf		
8.2 Qualification report and qualification results	Available (see attachment)	Issue Date	2019-07-04

9. Attachments (additional documentations)		
11662 Public product.pdf 11662 U1K2 Muar FT Additional Testing Platform_official_summary.pdf		
10. Affected parts		
10. 1 Current		10.2 New (if applicable)
10.1.1 Customer Part No	10.1.2 Supplier Part No	10.1.2 Supplier Part No
	ALED1262ZTTR	

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## Public Products List

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**PCN Title :** Power Management BU: Additional tester for Test & Finishing in Muar for ALED1262xx product Family.

**PCN Reference :** AMS/19/11662

**Subject :** Public Products List

Dear Customer,

Please find below the Standard Public Products List impacted by the change.

ALED1262ZTTR		
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# U1K2 Muar FT additional testing platform

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Operation and AMG / GPA Product Engineer Department  
W22 2019

## □ GOAL

Based on the requested demand for increased FT production capacity we developed a new testing solution based on a different ATE

## □ ATE

- ✓ Standard tester SZ Advantest M36x0 (testing cluster // by2)
- ✓ Additional tester Teradyne Eagle ETS364 (testing cluster // by4)

## □ FT Validation Process

- ✓ Robustness/Endurance Check
- ✓ FT comparison analysis btw SZ and ETS on 2 different FT lots (overall min qty 1kpcs).

# FT validation process: Method

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- ❑ 2 different assy lots for a total amount of at least 1Kpcs
- ❑ All the parts are:
  - All the parts are tested using the old and new platform alternatively
    - ✓ @amb temp
  - Collect testing data on the first equipment
  - Retest on the second equipment
  - Collecting testing data to correlate:
    - ✓ screening efficiency (good and bad)
    - ✓ parametric alignment



# FT validation process: Robustness/Endurance Check

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- ☐ Spike analysis
- ☐ Bin1 reliability

# Equipment qualification

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Test / Evaluation	Test Conditions / Parameters	Result
Spike analysys	Each pin is monitored during tp flow	Pass – no spikes over the Absolute Maximum Rating voltages
Reliability	300 loops on golden samples parts on all sites	Pass: no kill unit

## ALED1262X AMBIENT

# Lot# 9991524FRP

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☐ First test on SZ

☐ Retest on ETS

Part Type		ALED1262XTRA1				
Test Program		E1K2FAA1				
Lot ID		9991524FRP				
Diffusion ID		V583961M				
Tester Type		SZ		ETS 364 VS2015		
Tester ID		MUAM366A		MUAE364T13		
Handler ID		MULTITEST MT9928		MULTITEST MT9928		
Qty In		500		500		
Qty Out		494		493		
Yield		98,80%		98,60%		
SW/HW Bin	Bin name	Total Count	Fail Rate	Total Count	Fail Rate	Delta
5	Open	6	1,20%	6	1,20%	0,00%
20	Clock	0	0,00%	1	0,20%	0,20%

# Lot# 99918152RQ

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❑ First test on ETS

❑ Retest on SZ

Part Type	ALED1262XTRA1					
Test Program	E1K2FAA1					
Lot ID	99918152RQ named 99918152RZ on SZ retest					
Diffusion ID	V5845FCR					
Tester Type	ETS 364 VS2015		SZ			
Tester ID	MUAE364T13		MUAM366A			
Handler ID	MULTITEST MT9928		MULTITEST MT9308			
Qty In	1000		1000			
Qty Out	991		991			
Yield	99,10%		99,10%			
SW/HW Bin	Bin name	Total Count	Fail Rate	Total Count	Fail Rate	Delta
20	Freq/Timing	5	0,50%	7	0,70%	0,20%
21	Memories	1	0,10%	0	0,00%	0,10%
24	i2c_comError	0	0,00%	0	0,00%	0,00%
5	Open	1	0,10%	1	0,10%	0,00%
6	Short	1	0,10%	1	0,10%	0,00%
8	Bandgap	1	0,10%	0	0,00%	0,10%